
Appendix E: Model Parameter Binning

Below is the information on parameter binning regarding which model parameters can or cannot be binned. All those parameters which can be binned follow this implementation:

$$P = P_0 + \frac{P_L}{L_{eff}} + \frac{P_W}{W_{eff}} + \frac{P_P}{L_{eff} \times W_{eff}}$$

For example, for the parameter $k1$: $P_0 = k1$, $P_L = lk1$, $P_W = wk1$, $P_P = pk1$. $binUnit$ is a binning unit selector. If $binUnit = 1$, the units of L_{eff} and W_{eff} used in the binning equation above have the units of microns; otherwise in meters.

For example, for a device with $L_{eff} = 0.5\mu m$ and $W_{eff} = 10\mu m$. If $binUnit = 1$, the parameter values for $vsat$ are $1e5$, $1e4$, $2e4$, and $3e4$ for $vsat$, $lvsat$, $wvsat$, and $pvsat$, respectively. Therefore, the effective value of $vsat$ for this device is

$$vsat = 1e5 + 1e4/0.5 + 2e4/10 + 3e4/(0.5*10) = 1.28e5$$

To get the same effective value of $vsat$ for $binUnit = 0$, the values of $vsat$, $lvsat$, $wvsat$, and $pvsat$ would be $1e5$, $1e-2$, $2e-2$, $3e-8$, respectively. Thus,

$$vsat = 1e5 + 1e-2/0.5e-6 + 2e-2/10e-6 + 3e-8/(0.5e-6 * 10e-6) = 1.28e5$$

Model parameters that have been binned in B4SOI are listed as follows:

E.1. DC Parameters

Symbol used in equation	Symbol used in SPICE	Description
V_{th0}	vth0	Threshold voltage @ $V_{bs}=0$ for long and wide device
K_1	k1	First order body effect coefficient
K_{1w1}	k1w1	First body effect width dependent parameter
K_{1w2}	k1w2	Second body effect width dependent parameter
K_2	k2	Second order body effect coefficient
K_3	k3	Narrow width coefficient
K_{3b}	k3b	Body effect coefficient of k3
K_{b1}	Kb1	Backgate body charge coefficient
W_0	w0	Narrow width parameter
N_{LX}	nlx	Lateral non-uniform doping parameter
D_{vt0}	Dvt0	first coefficient of short-channel effect on Vth
D_{vt1}	dvt1	Second coefficient of short-channel effect on Vth
D_{vt2}	dvt2	Body-bias coefficient of short-channel effect on Vth
D_{vt0w}	dvt0w	first coefficient of narrow width effect on Vth for small channel length
D_{vt1w}	dvt1w	Second coefficient of narrow width effect on Vth for small channel length
D_{vt2w}	dvt2w	Body-bias coefficient of narrow width effect on Vth for small channel length
μ_0	u0	Mobility at Temp = Tnom
U_a	ua	First-order mobility degradation coefficient
U_b	ub	Second-order mobility degradation coefficient
U_c	uc	Body-effect of mobility degradation coefficient
v_{sat}	vsat	Saturation velocity at Temp=Tnom
$A0$	a0	Bulk charge effect coefficient for channel length

A_{gs}	ags	Gate bias coefficient of A_{bulk}
$B0$	b0	Bulk charge effect coefficient for channel width
$B1$	b1	Bulk charge effect width offset
$Keta$	keta	Body-bias coefficient of bulk charge effect
$Ketas$	Ketas	Surface potential adjustment for bulk charge effect
A_1	A1	First non-saturation effect parameter
A_2	A2	Second non-saturation effect parameter
R_{dsw}	rds	Parasitic resistance per unit width
$Prwb$	prwb	Body effect coefficient of R_{dsw}
$Prwg$	prwg	Gate bias effect coefficient of R_{dsw}
Wr	wr	Width offset from W_{eff} for R_{ds} calculation
$Nfactor$	nfactor	Subthreshold swing factor
$Wint$	wint	Width offset fitting parameter from I-V without bias
$Lint$	lint	Length offset fitting parameter from I-V without bias
DWg	dwg	Coefficient of W_{eff} 's gate dependence
DWb	dwb	Coefficient of W_{eff} 's substrate body bias dependence
V_{off}	voff	Offset voltage in the subthreshold region for large W and L
$Eta0$	eta0	DIBL coefficient in subthreshold region
$Etab$	etab	Body-bias coefficient for the subthreshold DIBL effect
D_{sub}	dsub	DIBL coefficient exponent
C_{it}	cit	Interface trap capacitance
C_{dsc}	cdsc	Drain/Source to channel coupling capacitance
C_{dscb}	cdscb	Body-bias sensitivity of C_{dsc}
C_{dsd}	cdsd	Drain-bias sensitivity of C_{dsc}
P_{clm}	pclm	Channel length modulation parameter
P_{dibl1}	pdibl1	First output resistance DIBL effect correction parameter
P_{dibl2}	pdibl2	Second output resistance DIBL effect correction parameter
D_{rout}	drout	L dependence coefficient of the DIBL correction parameter in R_{out}
$Pvag$	pvag	Gate dependence of Early voltage

δ	delta	Effective V_{ds} parameter
α_0	alpha0	The first parameter of impact ionization current
F_{bjtii}	fbjtii	Fraction of bipolar current affecting the impact ionization
β_0	beta0	First V_{ds} dependent parameter of impact ionization current
β_1	beta1	Second V_{ds} dependent parameter of impact ionization current
β_2	beta2	Third V_{ds} dependent parameter of impact ionization current
$V_{dsatii0}$	vdsatii0	Nominal drain saturation voltage at threshold for impact ionization current
T_{ii}	tii	Temperature dependent parameter for impact ionization current
L_{ii}	lii	Channel length dependent parameter at threshold for impact ionization current
E_{satii}	esatii	Saturation channel electric field for impact ionization current
S_{ii0}	sii0	First V_{gs} dependent parameter for impact ionization current
S_{ii1}	sii1	Second V_{gs} dependent parameter for impact ionization current
S_{ii2}	sii2	Third V_{gs} dependent parameter for impact ionization current
S_{iid}	siid	V_{ds} dependent parameter of drain saturation voltage for impact ionization current
α_{gidl}	Agidl	GIDL constant
β_{gidl}	Bgidl	GIDL exponential coefficient
χ	Ngidl	GIDL V_{ds} enhancement coefficient
n_{tun}	Ntun	Reverse tunneling non-ideality factor
n_{diode}	Ndiode	Diode non-ideality factor
n_{recf0}	Nrecf0	Recombination non-ideality factor at forward bias
n_{recr0}	Nrecr0	Recombination non-ideality factor at reversed bias
i_{sbjt}	Isbjt	BJT injection saturation current
i_{sdif}	Isdif	Body to source/drain injection saturation current
i_{srec}	Isrec	Recombination in depletion saturation current
i_{stun}	Istun	Reverse tunneling saturation current
V_{rec0}	Vrec0	Voltage dependent parameter for recombination current

V_{tun0}	Vtun0	Voltage dependent parameter for tunneling current
N_{bjt}	Nbjt	Power coefficient of channel length dependency for bipolar current
L_{bjt0}	Lbjt0	Reference channel length for bipolar current
V_{abjt}	Vabjt	Early voltage for bipolar current
A_{ely}	Aely	Channel length dependency of early voltage for bipolar current
A_{hli}	Ahli	High level injection parameter for bipolar current

E.2. AC and Capacitance Parameters

Symbol used in equation	Symbol used in SPICE	Description
V_{sdfb}	vsdfb	Source/drain bottom diffusion capacitance flatband voltage
V_{sdth}	vsdth	Source/drain bottom diffusion capacitance threshold voltage
$DelVt$	delvt	Threshold voltage adjust for C-V
$acde$	acde	Exponential coefficient for charge thickness in capMod=3 for accumulation and depletion regions.
$moin$	moin	Coefficient for the gate-bias dependent surface potential.